



DOCTORATE PROGRAM IN **ELECTRONIC ENGINEERING**

DOCTORAL TRAINING SEMINARS: RESEARCH PROJECTS IN
THE DEPARTMENT OF ELECTRONIC ENGINEERING

**“Cost-effective technologies for crystalline
silicon (c-Si) solar cells”**

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11th February 2014

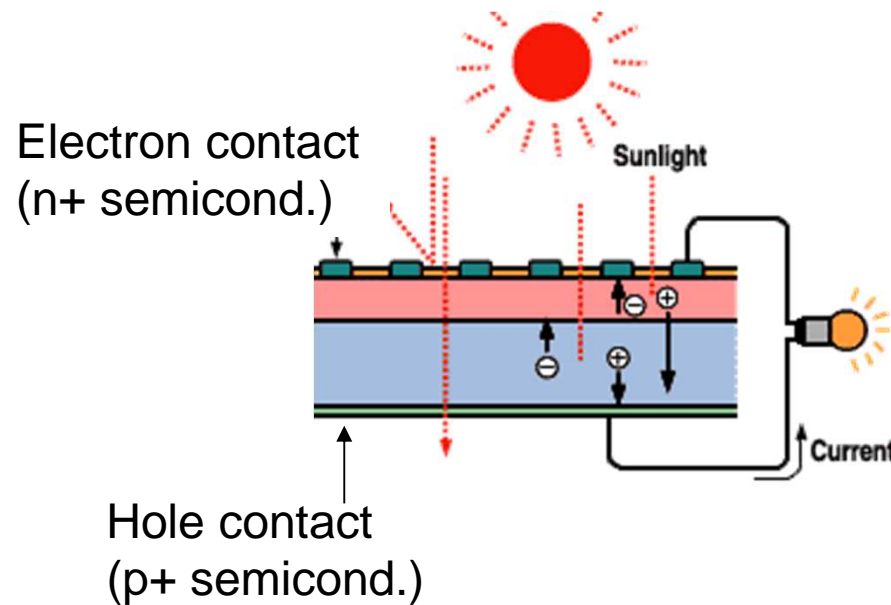
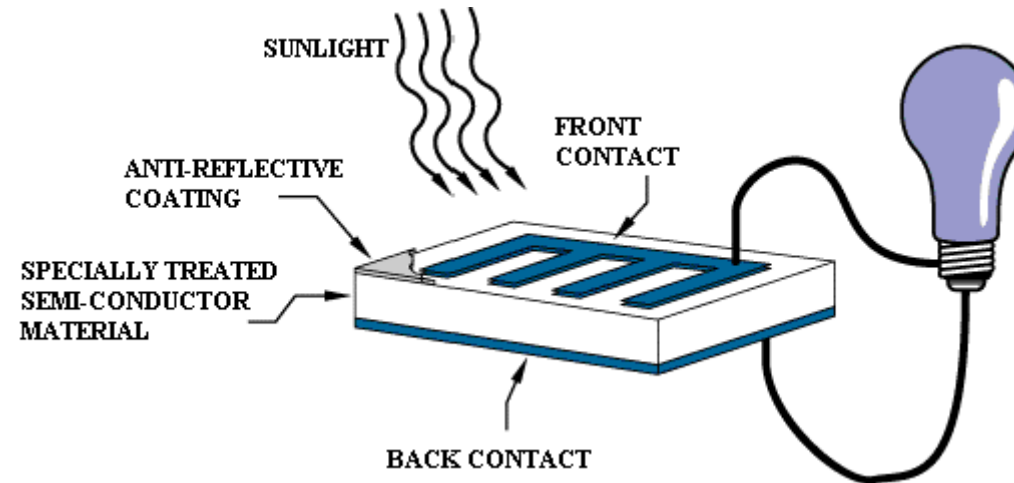
PROGRAMA DE DOCTORAT EN **ENGINYERIA ELECTRÒNICA**

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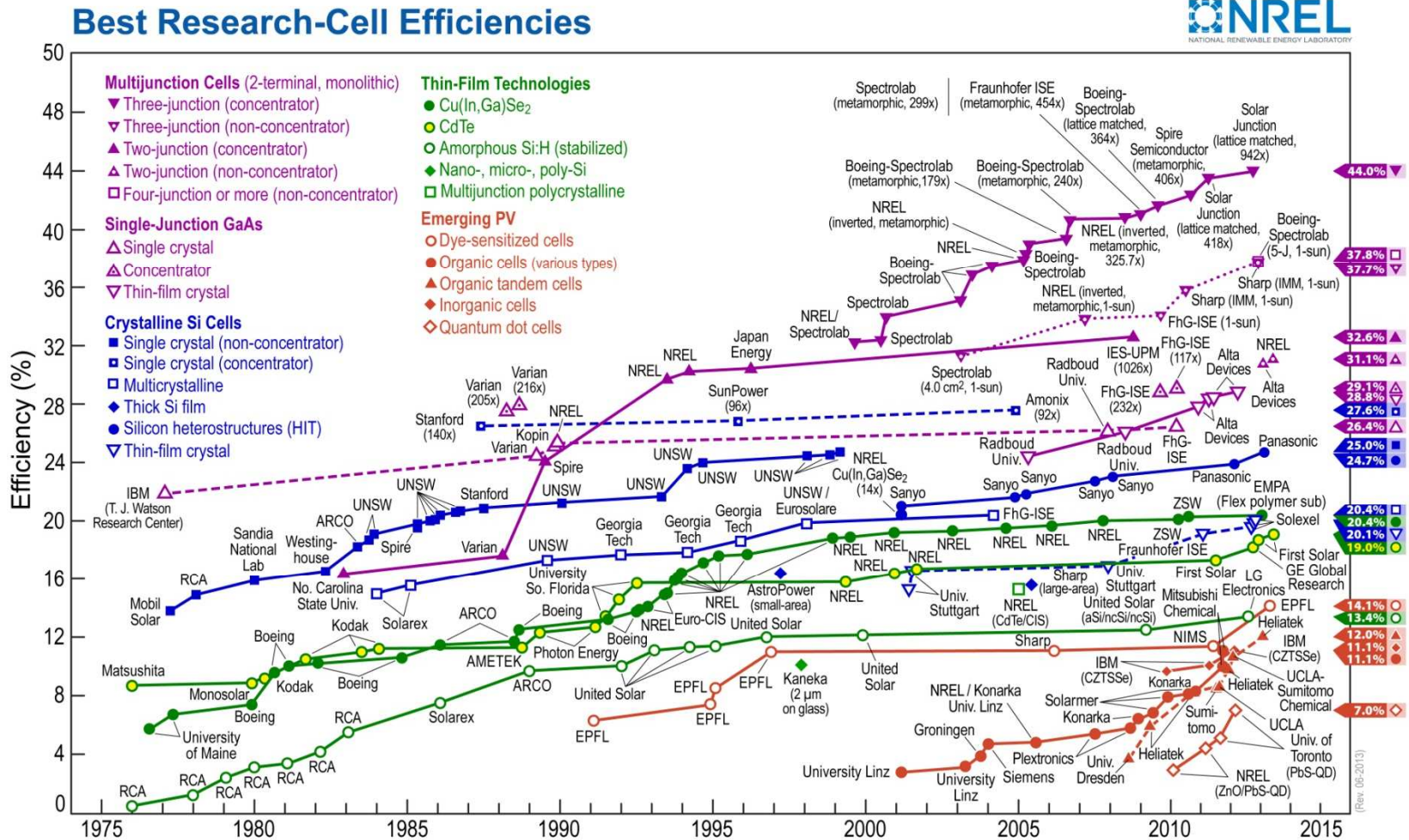
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2. Laser processing applied to rear contact schemes
 - Laser fired contacts with Al films
 - Laser doped regions from dielectric films: Al_2O_3 and $\text{SiC}_x(\text{n})$ films.
3. Fully low temperature structures
 - DopLa (Doped by Laser) cell.
 - IBC (Interdigitated Back Contacted) cell.
 - Silicon Heterojunction solar cells.
4. Very thin c-Si wafers: mille-feuille concept
5. Resources

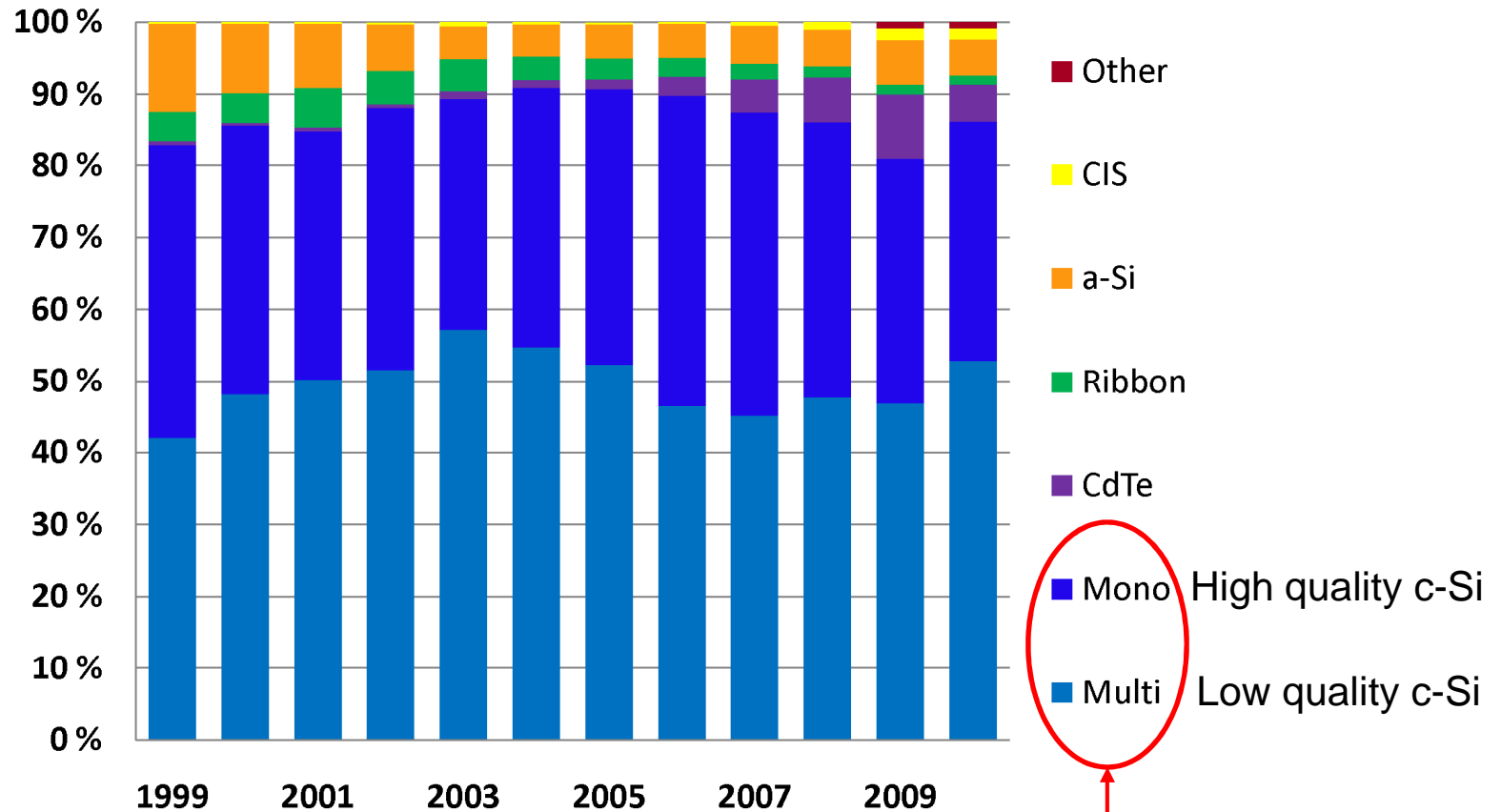
Photovoltaic effect



Many technologies involved

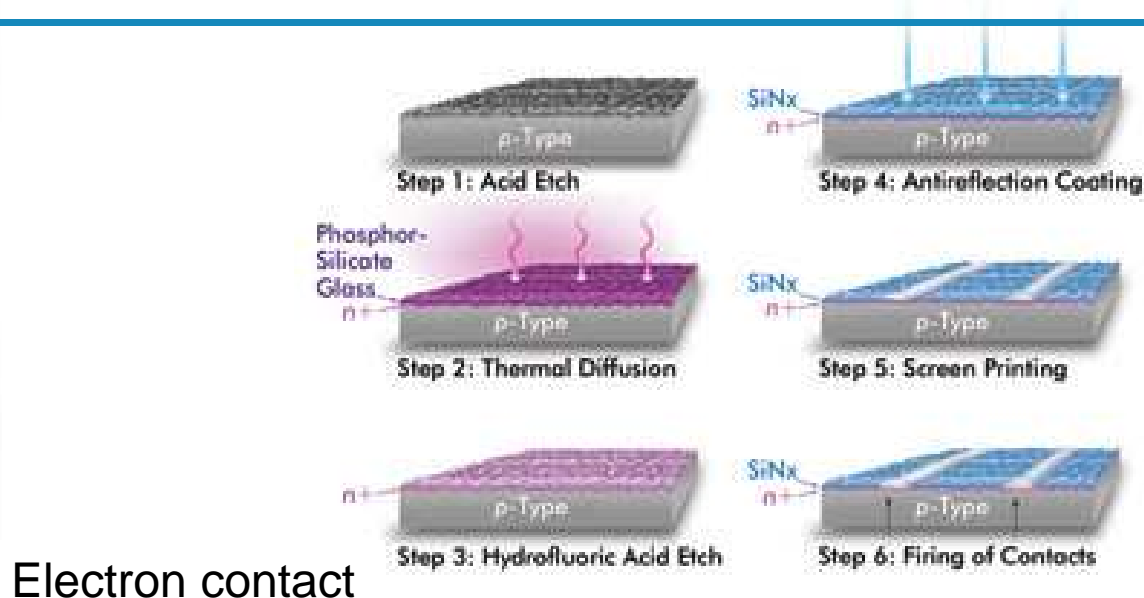


Terrestrial applications market

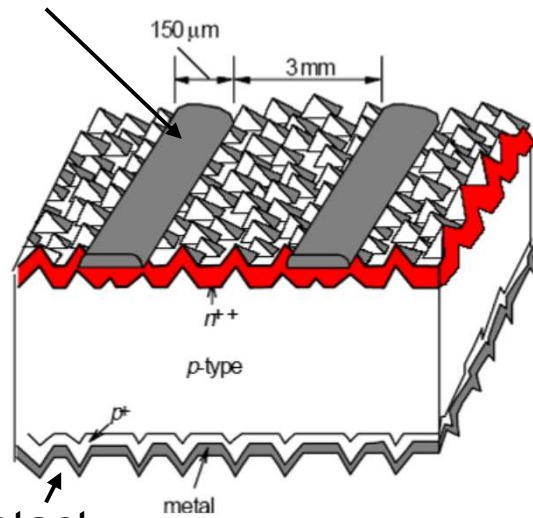


- **Costs** is a driving force (€/Wp)
- Crystalline silicon shares more than 80 % of the market

Very simple fabrication process



Electron contact



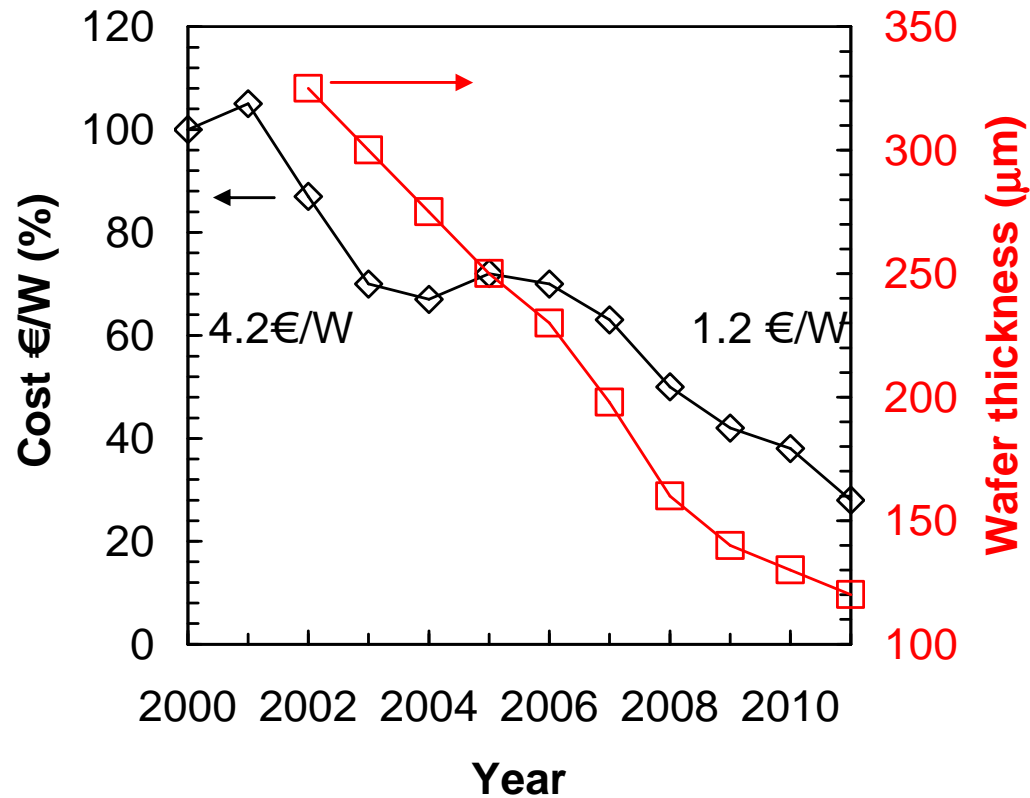
Hole contact

Main costs:

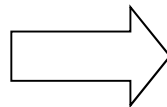
- c-Si wafer.
- High temperature steps for the creation of the highly-doped regions.

Thinner wafers

Source: SiGen



Silicon is about the 40% of the cost



Reduction of the wafer thickness



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Problems with full Al p+ contact

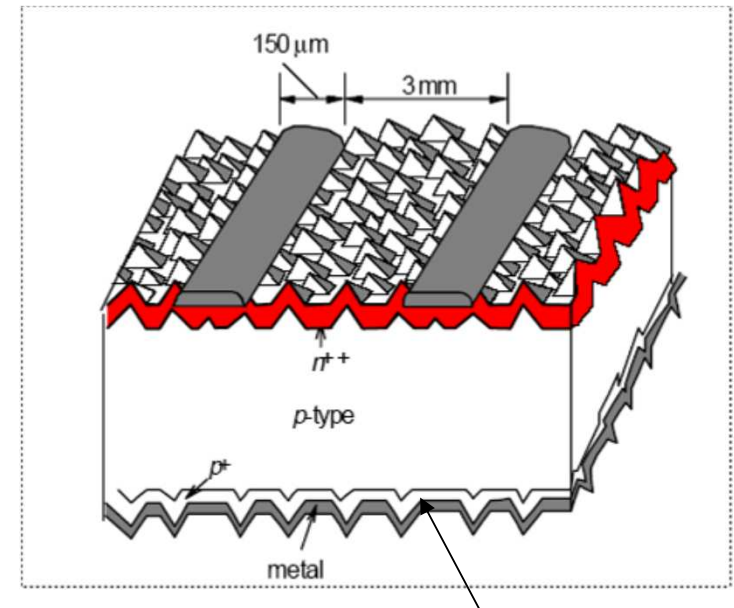
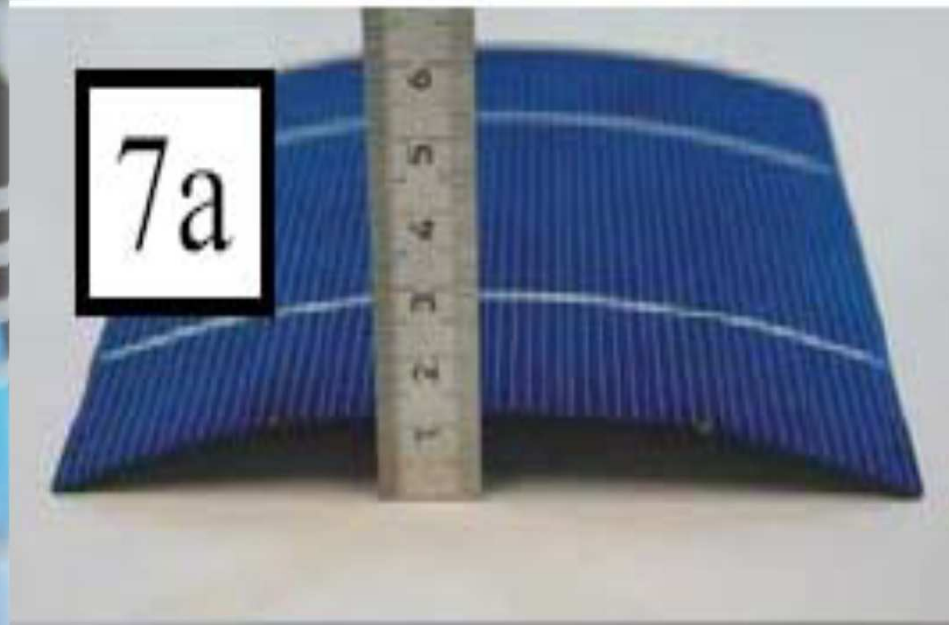
Scenary of the commercial c-Si solar cells:

Limited by the surface recombination at the back contact

Lower costs (more wafers per ingot)

Thinner substrates

$L_D > W$

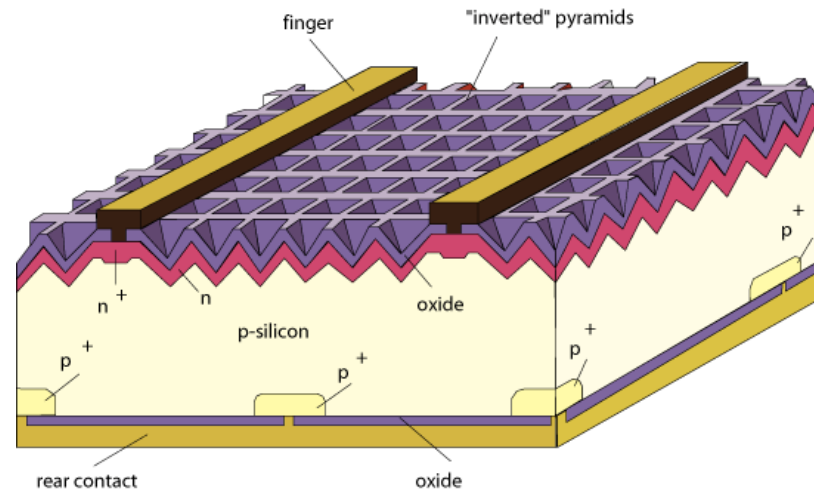


$S_{eff} \sim 10^4 \text{ cm/s}$

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Adptation of PERL concept to thin industrial substrates



- Applied to the world record c-Si solar cell (24.7%, UNSW).
- Rear side passivation based on dielectric layer and point contact.
- Dielectric film (SiO_2) thermally grown at $\sim 1100^\circ\text{C}$ ☹️
- p+ regions created by high temperature step ☹️
- Definition of the contacts by lithography ☹️

J. Zhao, A. Wang and M.A. Green. Prog. Photovolt.: Res. Appl. 1999;7: 471-474.

MNT activities in c-Si solar cells

Main objective: development of cost-effective technologies to create p+ and n+ regions and compatibles with thin substrates.

Laser processing applied to rear contact schemes:

- p+ regions: laser fired contacts with Al and Al₂O₃ films.
- n+ regions: laser doping from SiC_x(n) films.

Fully low temperature structures:

- DopLa (Doped by Laser) cell.
- IBC (Interdigitated Back Contacted) cell.
- Silicon Heterojunction solar cells.

Fabrication of very thin c-Si wafers, the “Mille-Feuille” concept.

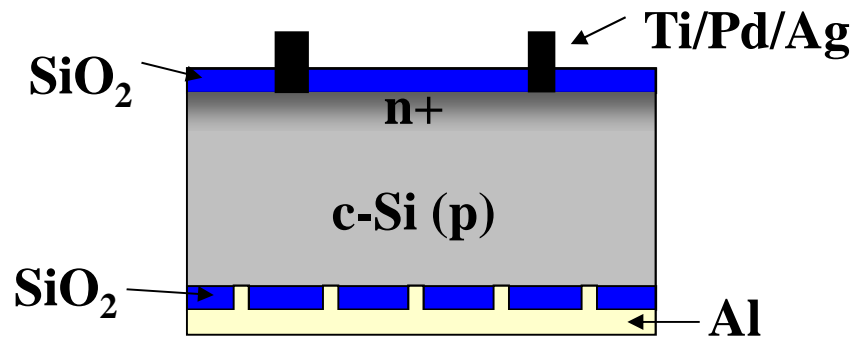
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Base line process

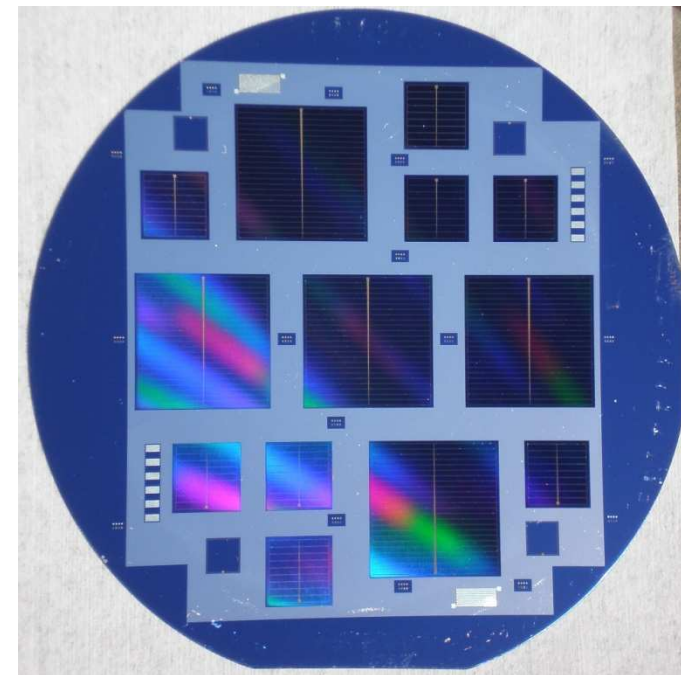
We use it as a reference technology, based on PERC structure (Passivated emitter and rear contact).

- Texturization by inverted pyramids.
- POCl_3 diffusion (850 °C).
- SiO_2 passivation (1070 °C).
- Front and back contact defined by lithography



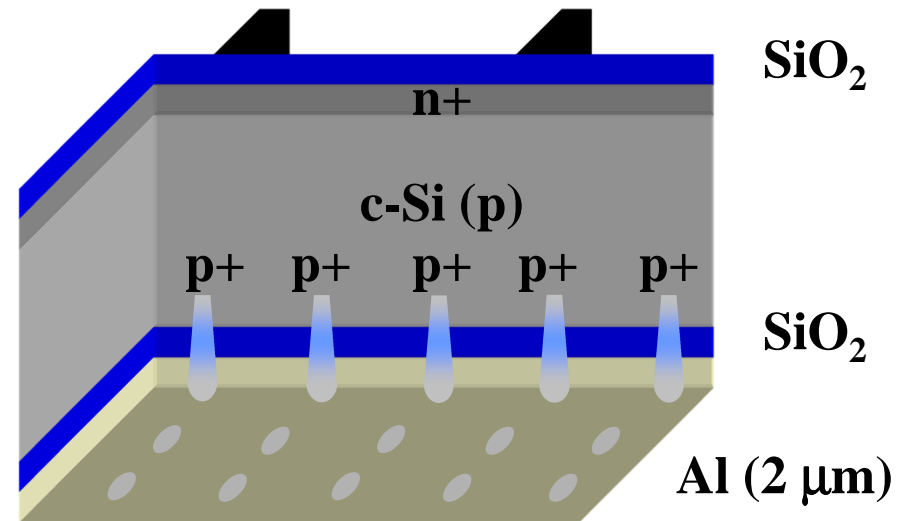
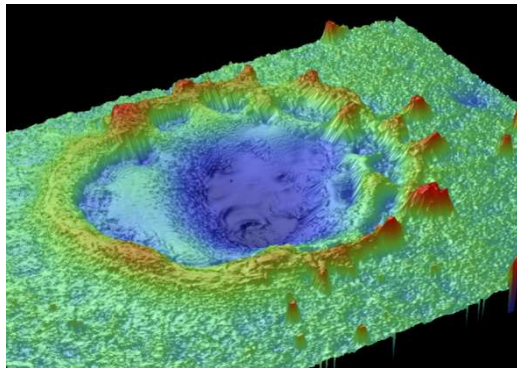
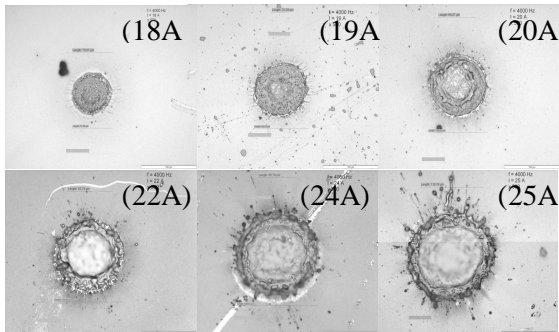
Best result:

| V_{oc} (mV) | J_{sc} (mA/cm ²) | FF (%) | η (%) |
|------------------|-----------------------------------|-----------|---------------|
| 628 | 39.0 | 75.9 | 18.6 |



Laser Fired Contacts

Replacement of lithography for the rear contact definition by Laser Fired Contacts (LFC).



Best result (1 mm pitch on p-type 0.45 Ω cm c-Si):

| V_{oc} (mV) | J_{sc} (mA/cm ²) | FF (%) | η (%) |
|------------------|-----------------------------------|-----------|---------------|
| 670 | 38.4 | 80.5 | 20.7 |

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c-Si surface passivation

We want to replace thermal SiO₂ by low temperature deposited films

- PECVD: a-SiC_x, a-SiC_xN_y and a-SiC_x(n)

$S_{\text{eff}} < 12 / 7 \text{ cm}\cdot\text{s}^{-1}$, for 1 $\Omega\cdot\text{cm}$ p/n type planar FZ c-Si substrates.

On industrial 1 $\Omega\cdot\text{cm}$ p-type CZ silicon, $S_{\text{eff}} = 220 \text{ cm}\cdot\text{s}^{-1}$ at 1 sun and passivation of 30 Ω/sq diffused emitters obtaining $J_{\text{oe}} = 250 \text{ fA}\cdot\text{cm}^{-2}$

- ALD: Al₂O₃

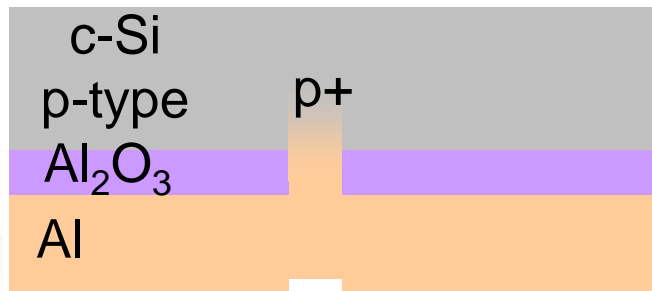
$S_{\text{eff}} < 2 / 10 \text{ cm}\cdot\text{s}^{-1}$, for 2.2 $\Omega\cdot\text{cm}$ p type planar/texturized FZ c-Si.

$S_{\text{eff}} < 1 \text{ cm}\cdot\text{s}^{-1}$, for 2.8 $\Omega\cdot\text{cm}$ n type planar FZ c-Si substrates.

Al₂O₃ and SiC_x(n) can simultaneously work as passivating films and dopant sources for laser processes.

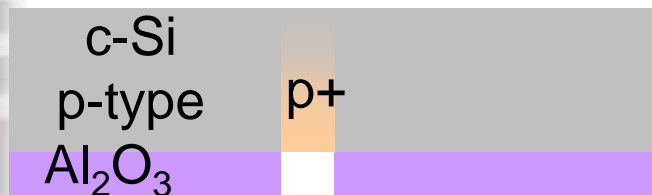
Advanced concept LFC

First approach:



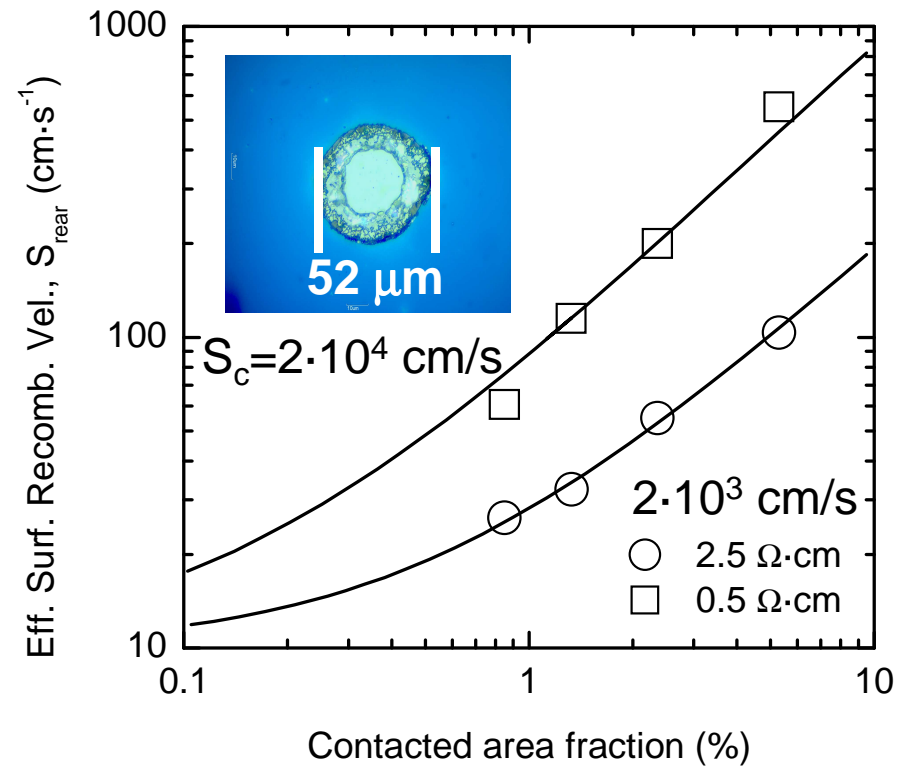
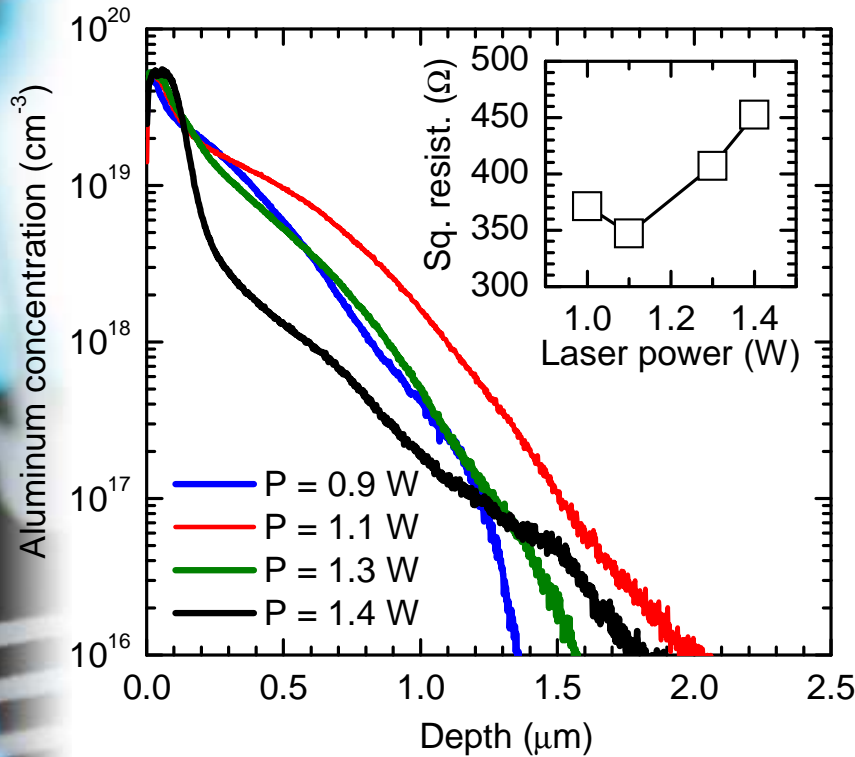
- High power laser process to break through the dielectric film.
- Prone to create crystal damage.
- Laser processing screen-printed Al pastes is difficult to the dependence on the Al thickness.

Advanced concept:



- Low power laser process just to melt the c-Si surface and ablate the dielectric
- Less crystal damage
- Better back reflector properties

High quality p+ regions



Soft laser processes result in p+ regions with very low S_{rear}

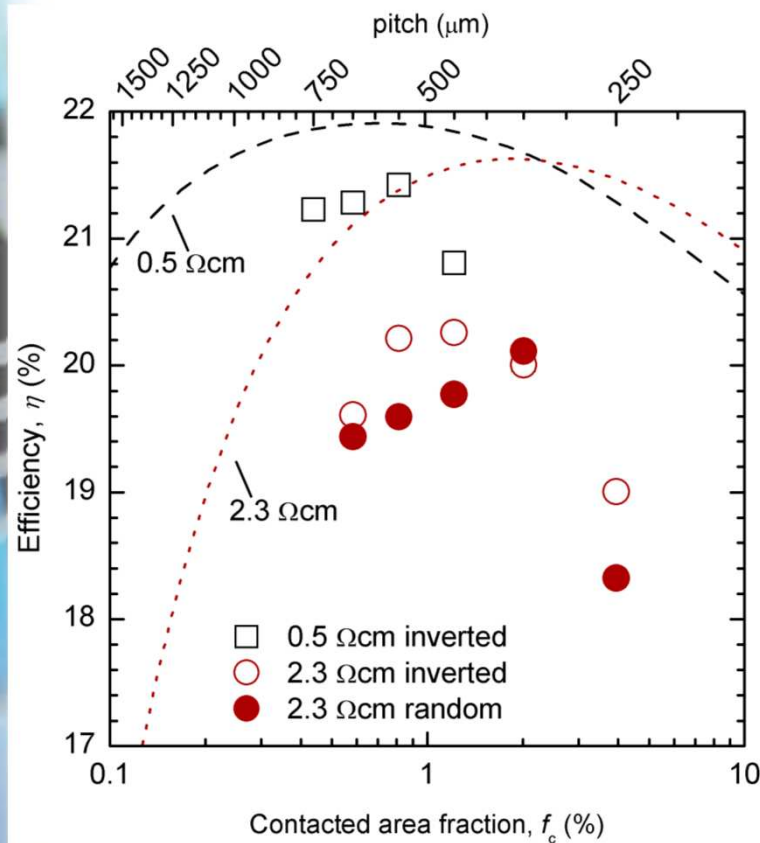
I. Martín et al., *Prog. Photovolt: Res. Appl.*, 21, 1171–1175 (2013).

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Application to solar cells

| Cell | ρ (Ωcm) | pyramids | p (μm) | f_c (%) | J_{sc} (mA/cm^2) | V_{oc} (mV) | FF (%) | η (%) |
|------|------------------------------|----------|-----------------------|-----------|--------------------------------------|---------------|--------|------------|
| #1 | 0.5 | inverted | 550 | 0.76 | 38.6 | 678 | 81.9 | 21.4 |
| #2 | 2.3 | inverted | 450 | 1.13 | 38.6 | 640 | 82.1 | 20.3 |
| #3 | 2.3 | random | 350 | 1.87 | 39.3 | 637 | 80.5 | 20.1 |



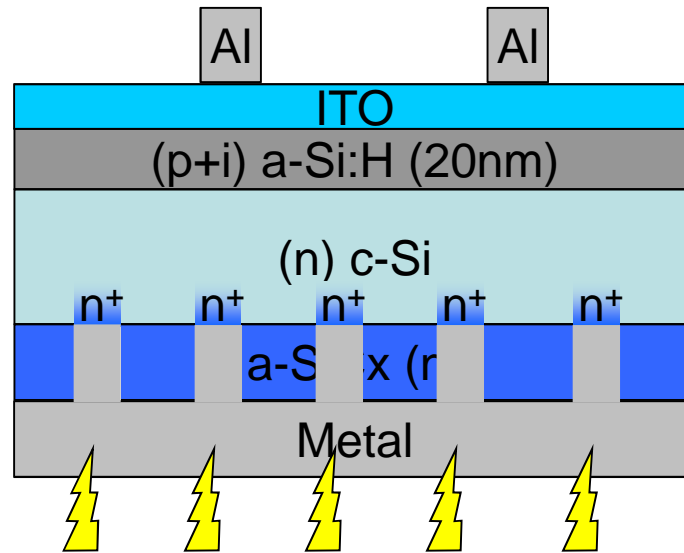
η beyond 21%! (only about 10 labs in the world have reached this efficiency)

- Better results than with conventional LFC process.
- Good results also in 2.3 Ωcm substrates.
- Main trend of the dependence of efficiency on pitch well modelled.

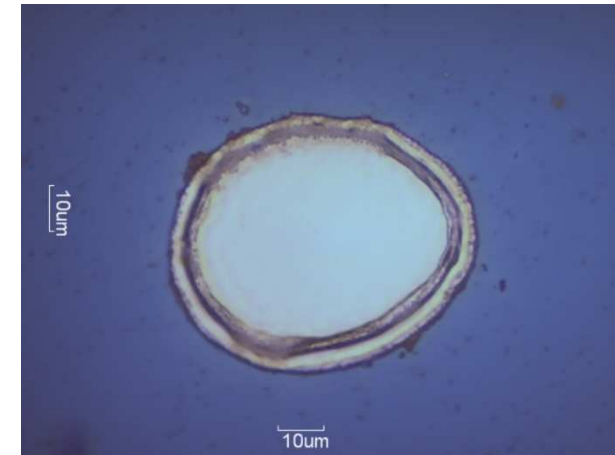
P. Ortega et al., Sol. Energy Mat. Sol. Cells 106, 80 (2012)

n^+ regions by laser doping from $\text{SiC}_x(\text{n})$

Applied to the rear surface of n-type HIT solar cells (LPICM, INES)



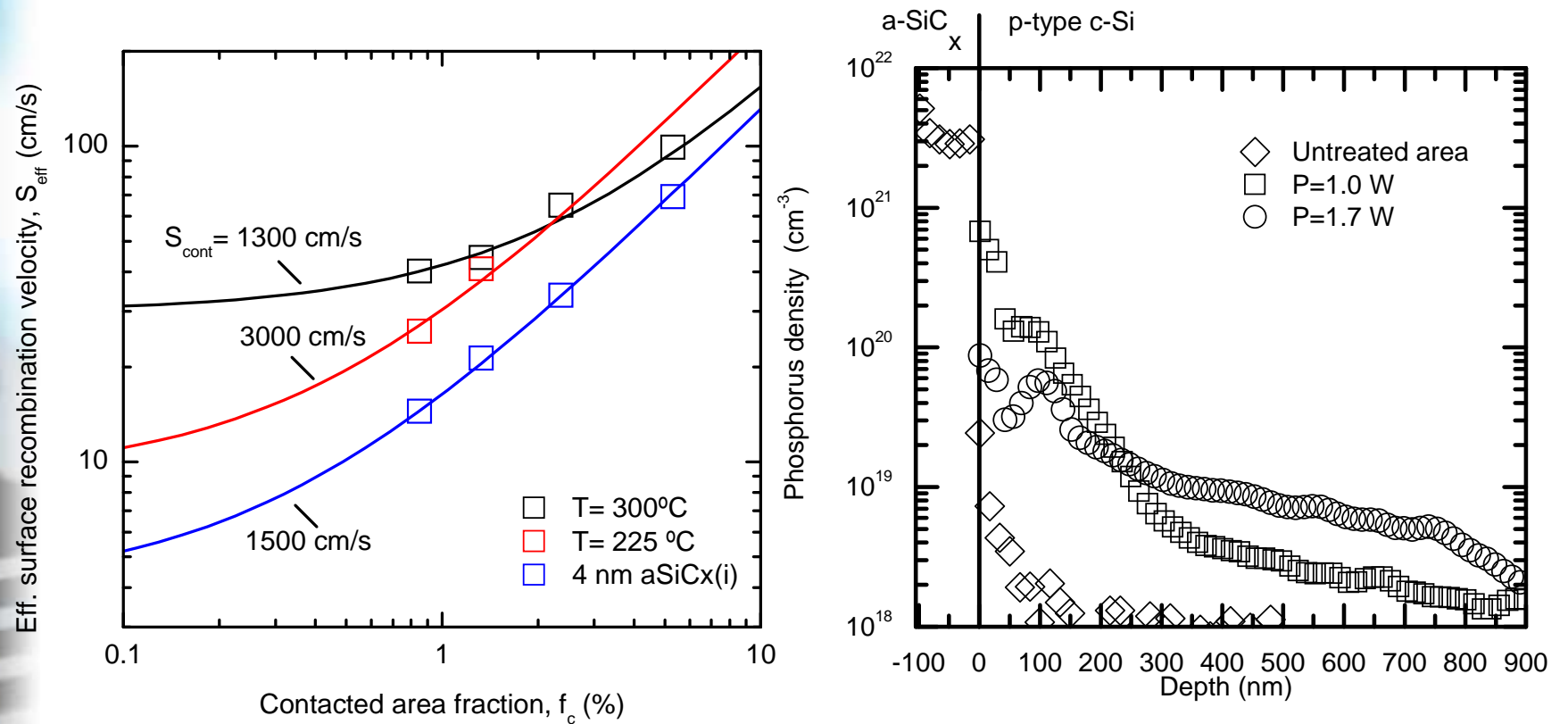
~50 μm \varnothing elliptical spots



The $\text{a-SiC}_x\text{:H}(\text{n})$ is a stack of three layers:

- Rear surface passivation: a thin (2 nm) intrinsic Si-rich $\text{a-SiC}_x\text{:H}$ film is previously deposited onto c-Si surface.
- Doping source: next 15 nm of Si-rich film with a high phosphorus content (1.8% of PH_3 in gas phase).
- Back reflector and electric isolation: finally a dielectric a-SiC_x film ($n=2.0$ and 80 nm) with phosphorus but in a much less percentage.

High quality n+ regions



| Rear configuration | J_{sc} (mA/cm^2) | V_{oc} (mV) | FF (%) | η (%) | pFF (%) | R_s ($\Omega \text{ cm}^2$) |
|-----------------------|---|------------------|-------------|---------------|--------------|------------------------------------|
| Amorphous BSF | 30.25 | 696 | 74.8 | 15.7 | 82.9 | 2.24 |
| SiC_x +laser | 30.05 | 672 | 72.5 | 14.6 | 80.5 | 2.22 |

I. Martín et al., presented at 27th EUPVSEC, Frankfurt (2012)

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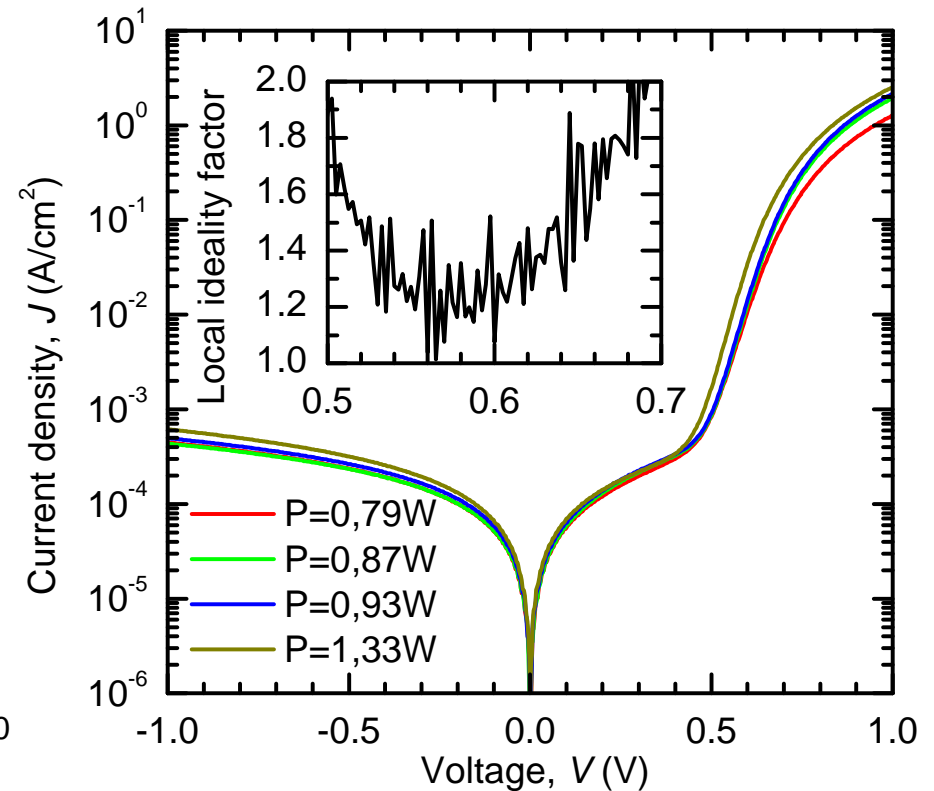
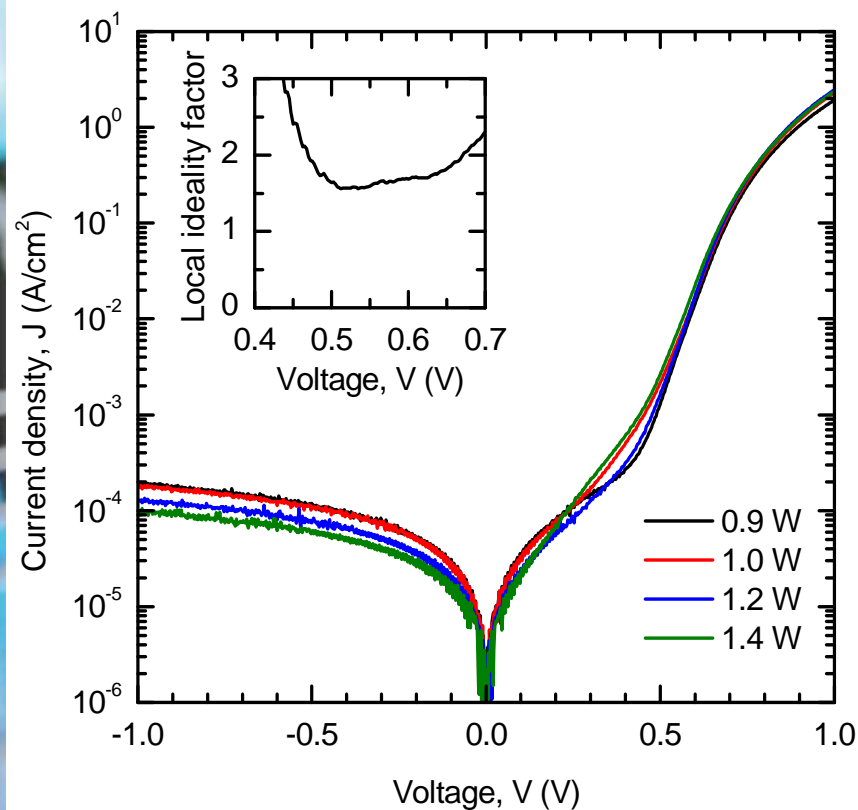
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n+/p and p+/n junctions

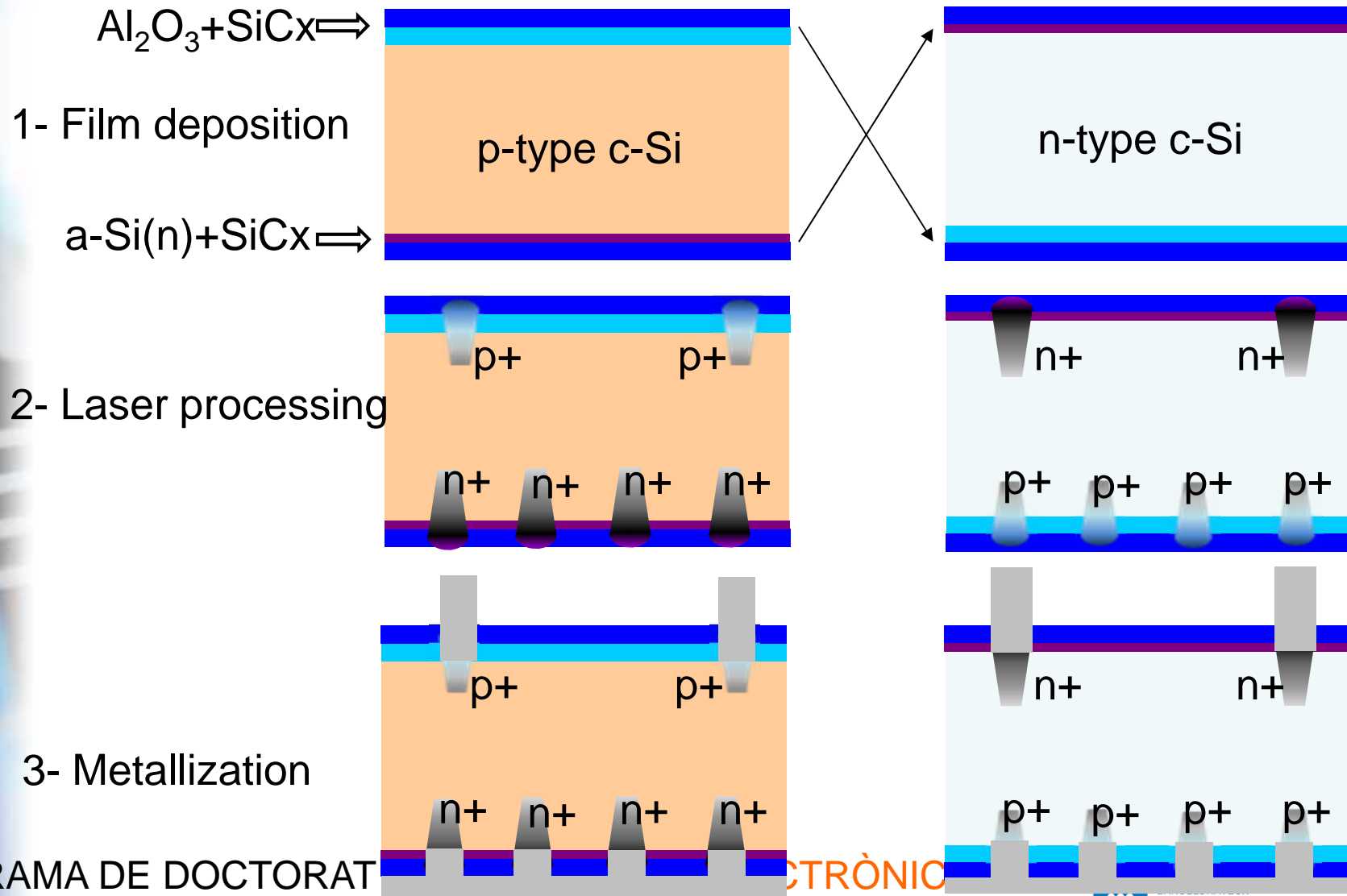
- n+ regions were formed from T=225 °C aSiC_x(n) stacks into p-type c-Si wafers.
- p+ regions are created from Al₂O₃/SiC_x stack into n-type c-Si wafers.



M. Colina et al., presented at 27th EUPVSEC, Frankfurt (2012)

DopLa cell concept

DopLa (Doped by Laser) cell: fully low temperature process without TCO



DopLa cell geometrical characteristics

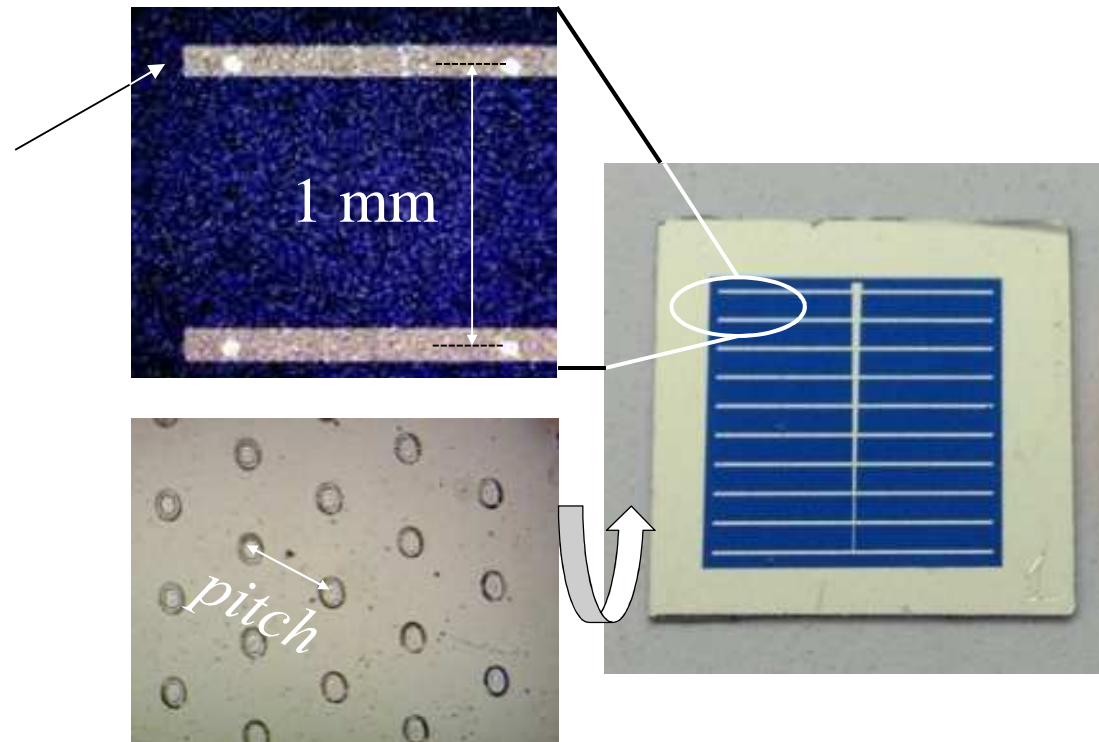
Main characteristics (1x1 cm² devices):

- Front surface: non-texturized surface, square matrixes with 1 mm pitch leading to 10 fingers.
- Rear surface: hexagonal matrixes with pitch ranging from 200 to 350 μm

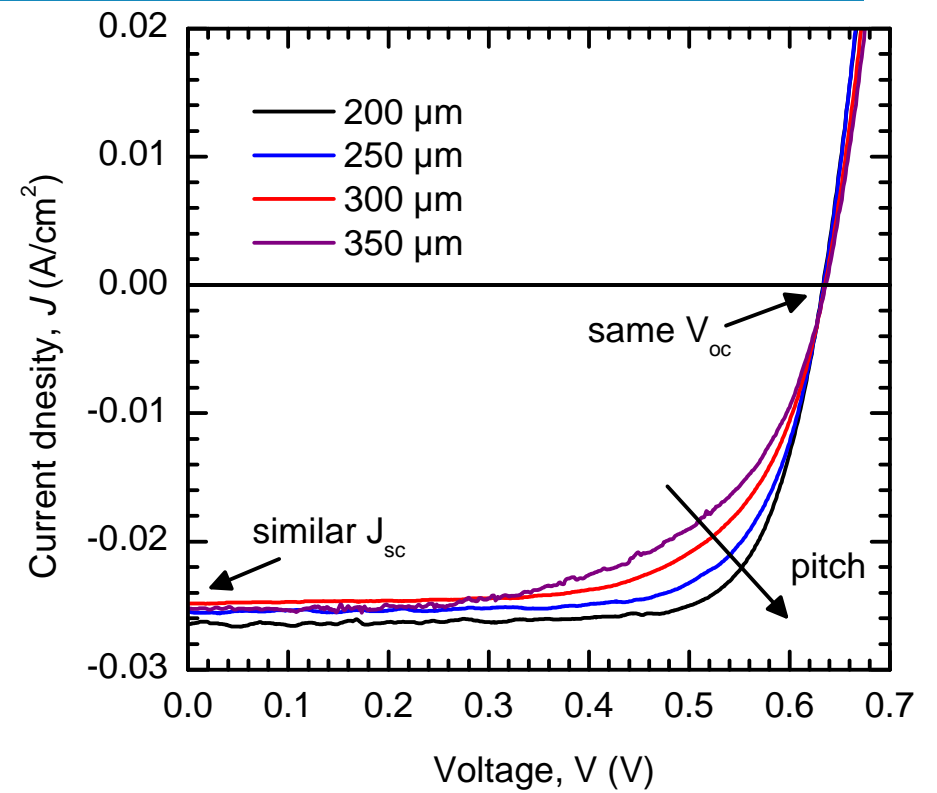
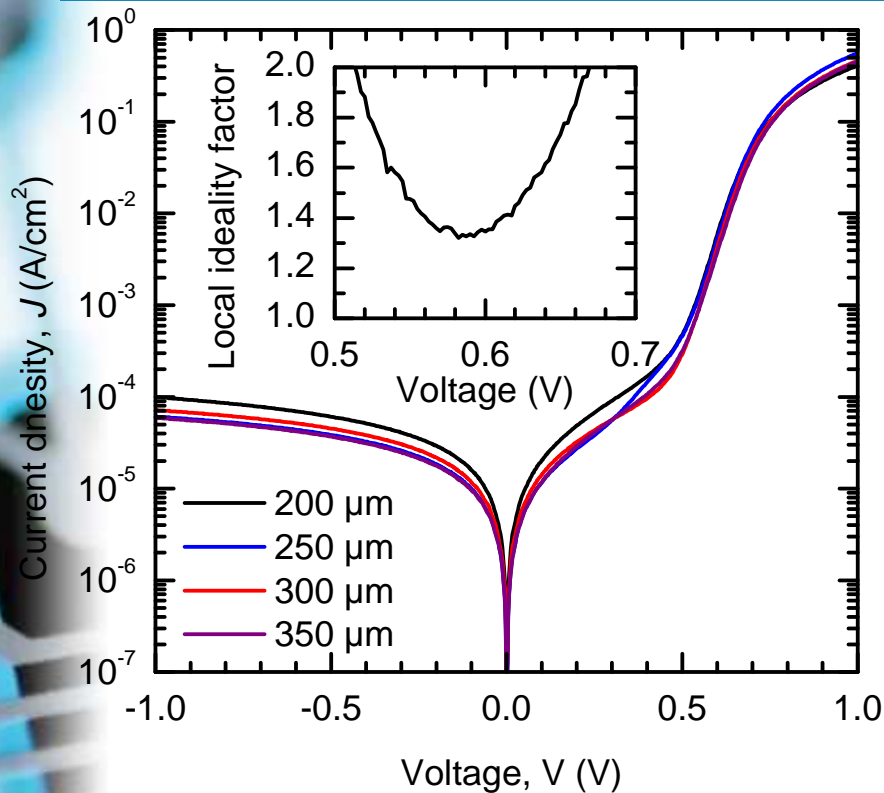
Shadow factor:

- 10 fingers 120 μm wide ($\approx 11.5\%$)
- Triangular bus bar ($\approx 1.3\%$)

Shadow $\approx 12.8\%$



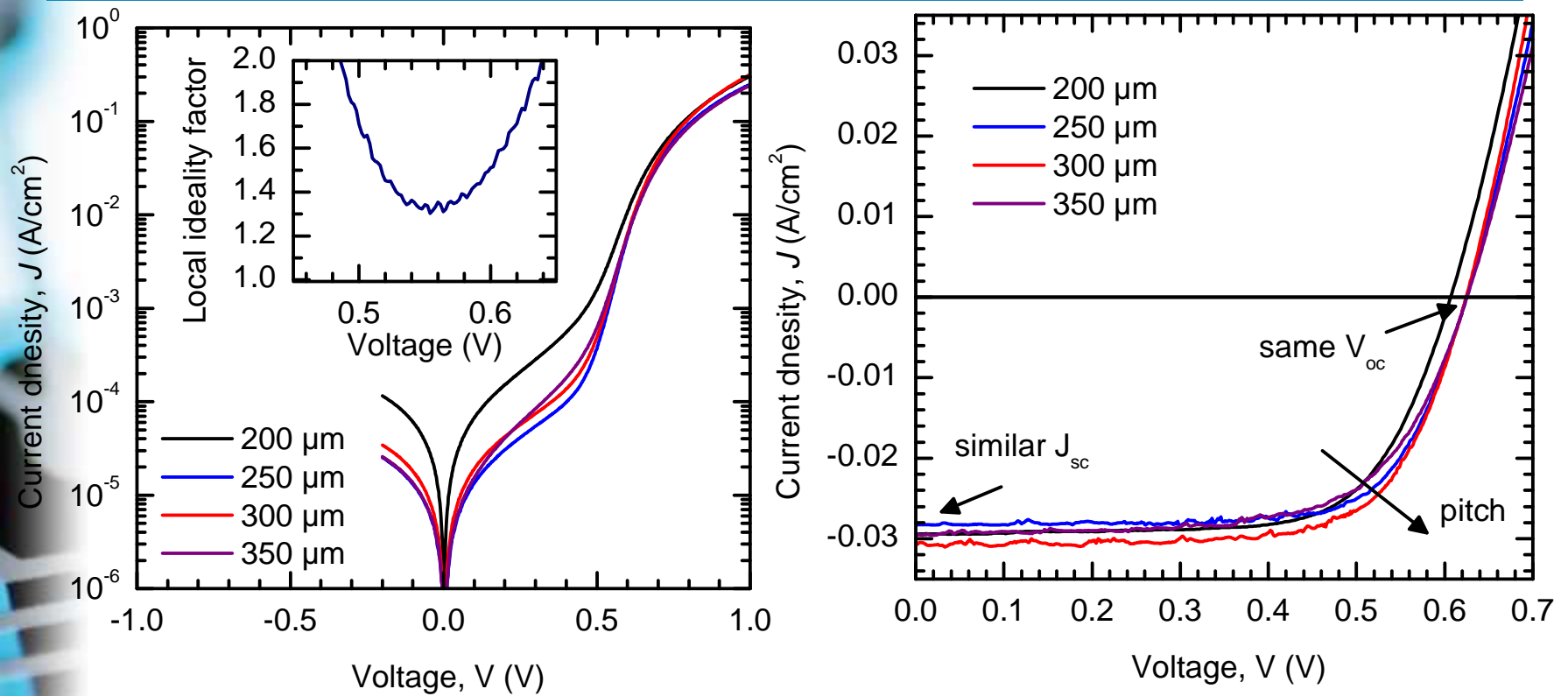
DopLa cells on p-type substrates



| Pitch (μm) | J_{sc} (mA/cm^2) | V_{oc} (mV) | FF (%) | η (%) |
|-------------------|------------------------|---------------|--------|--------------|
| 200 | 26.5 | 634 | 75.4 | 12.64 |
| 250 | 25.5 | 634 | 72.4 | 11.62 |
| 300 | 24.8 | 635 | 66.5 | 10.47 |
| 350 | 25.2 | 636 | 59.4 | 9.52 |

I. Martin et al.,
presented at 28th
EUPVSEC,
Paris (2013)

DopLa cells on n-type substrates



| Pitch (μm) | J_{sc} (mA/cm ²) | V_{oc} (mV) | FF (%) | η (%) |
|-------------------------|--------------------------------|---------------|--------|-------------|
| 200 | 29.5 | 608 | 68.5 | 12.3 |
| 250 | 28.2 | 625 | 71.3 | 12.6 |
| 300 | 30.6 | 625 | 69.5 | 13.3 |
| 350 | 29.5 | 625 | 65.0 | 12.0 |

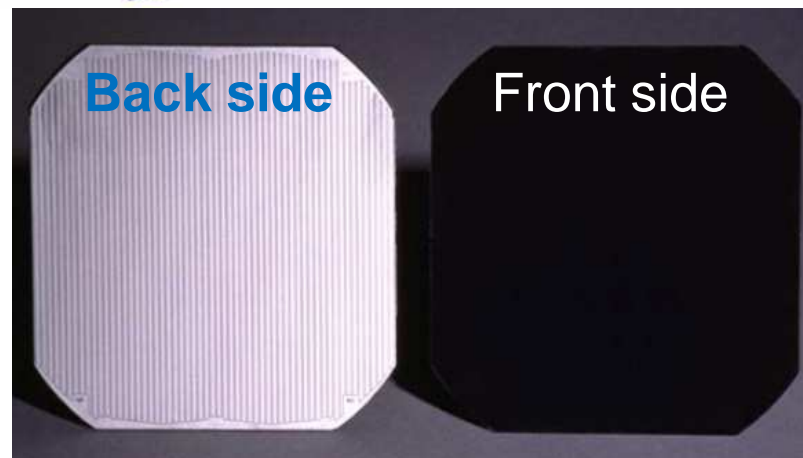
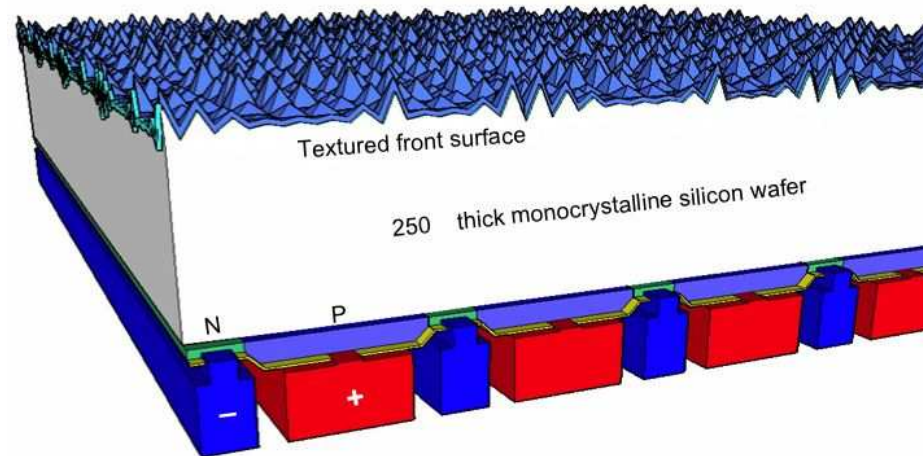
I. Martin et al.,
accepted in
4th SiliconPV,
's-Hertogenbosch (2014)

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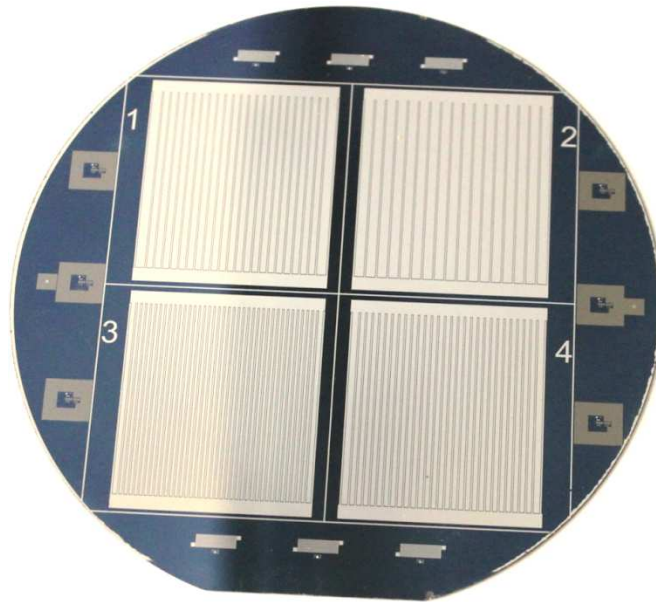
IBC solar cell concept

Interdigitated Back-Contacted (IBC) solar cell: all contacts at the rear surface, so no front metallization shadowing. Commercially available by SunPower with high efficiencies (>23%).

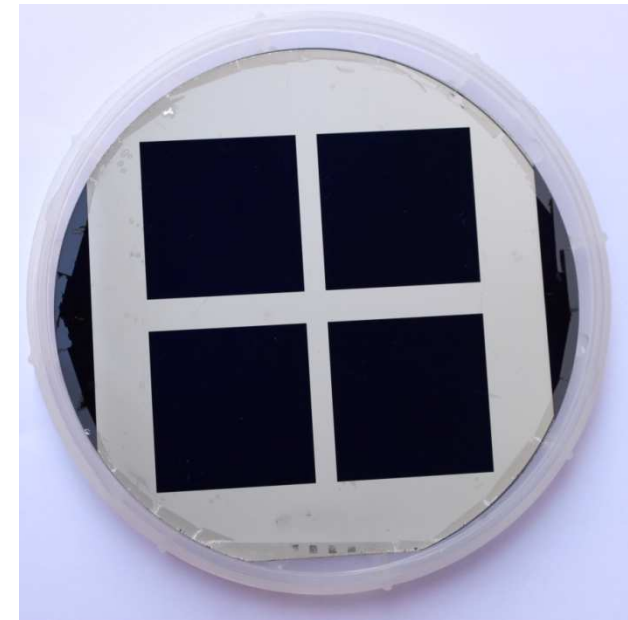


IBC base line process

Rear side (contacts side)
Reference wafer



Front side (illuminated side)
Reference wafer



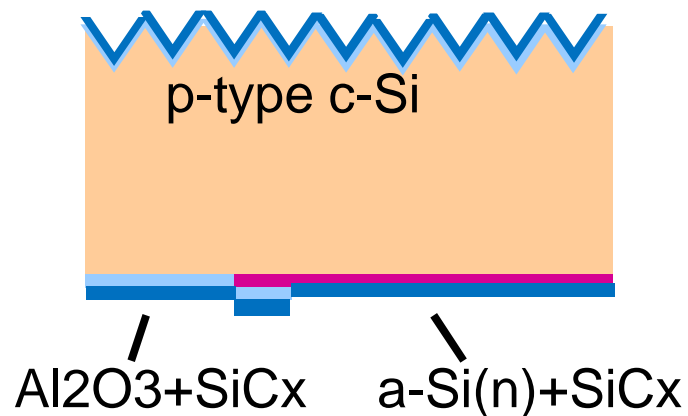
| Cell | Emitter coverage | J_{sc} (mA/cm ²) | V_{oc} (mV) | FF (%) | η (%) |
|------|------------------|--------------------------------|---------------|-------------|-------------|
| #2 | 86 % | 41.0 | 652 | 75.0 | 20.0 |
| #1 | 80 % | 40.9 | 651 | 72.4 | 19.3 |
| #4 | 75 % | 40.6 | 648 | 77.2 | 20.3 |
| #3 | 67 % | 40.0 | 644 | 77.1 | 19.9 |

$\eta > 20\%$ in c-Si IBC cells!
(only 5 labs in the world have reached this efficiency)

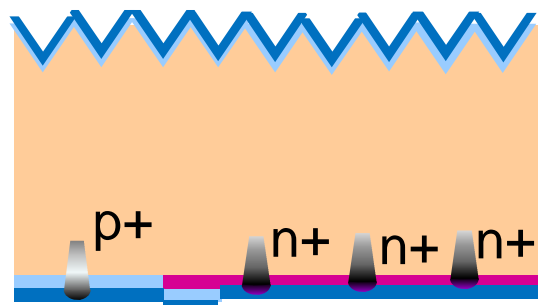
DopLa-IBC solar cell concept

Interdigitated Back Contact (IBC): definition of both p+ contacts and n+ emitters on the rear side of the cell. Patterning of the films by lithography and etching. No alignment of the laser needed. Fully low temperature.

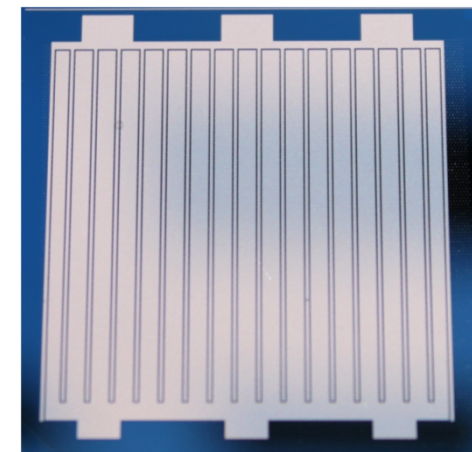
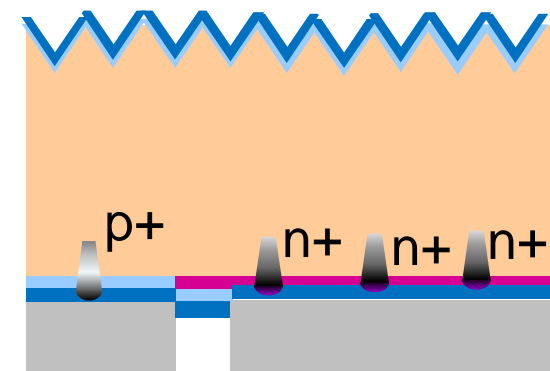
1- Film deposition and patterning



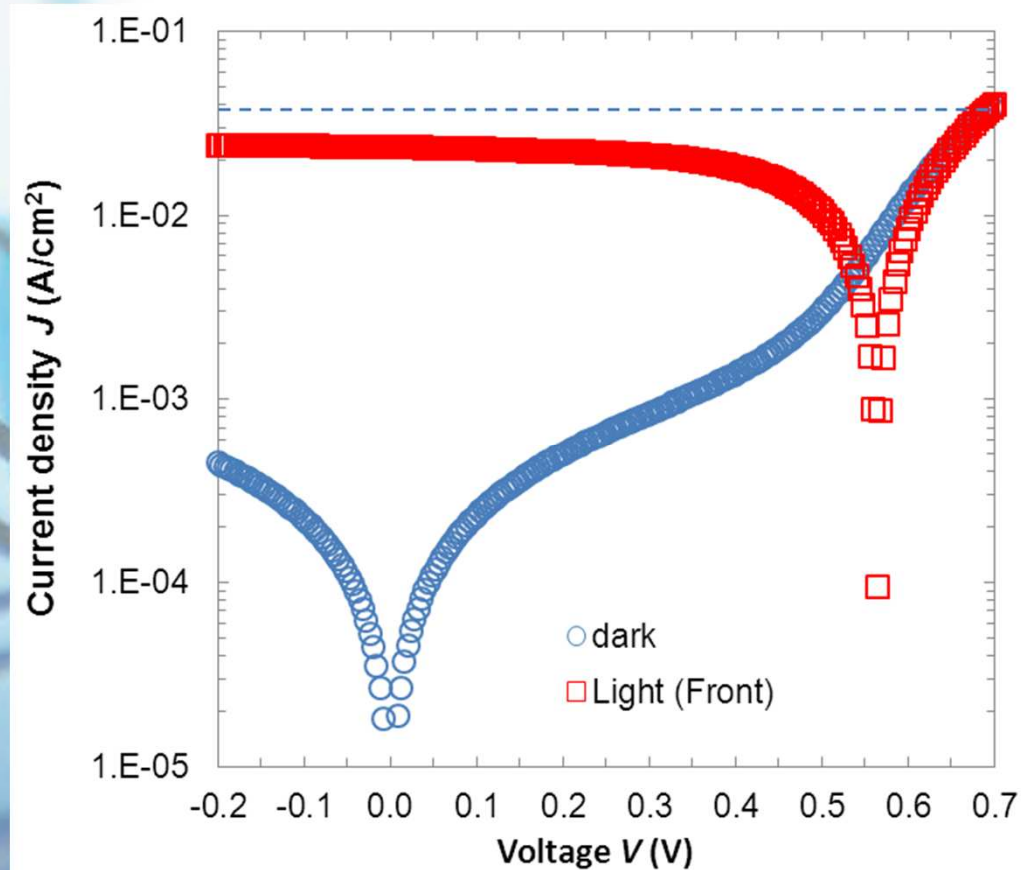
2- Laser processing



3- Metallization



DopLa-IBC cell results



Oblea 0.45 Ωcm

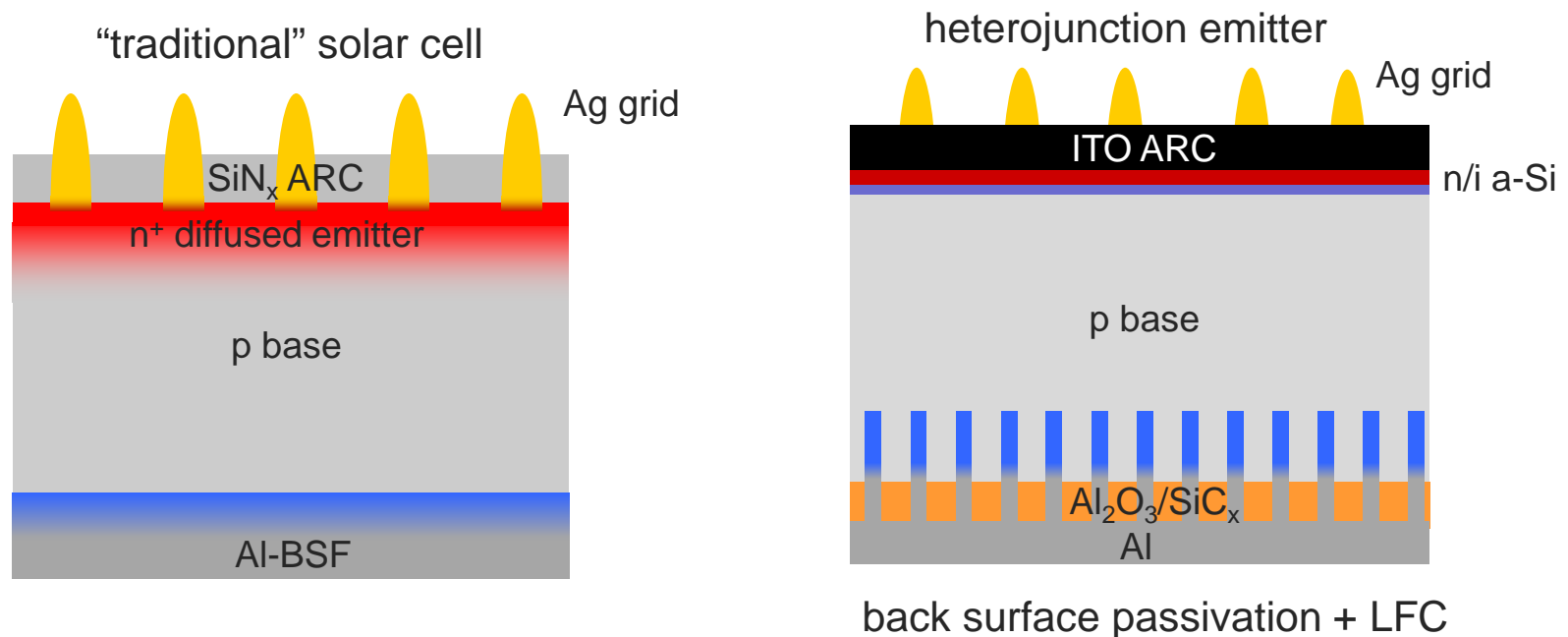
| J_{ph} (mA/cm ²) | V_{oc} (mV) | FF (%) | η (%) |
|--------------------------------|---------------|--------|------------|
| 21.4 | 564 | 60.3 | 7.3 |

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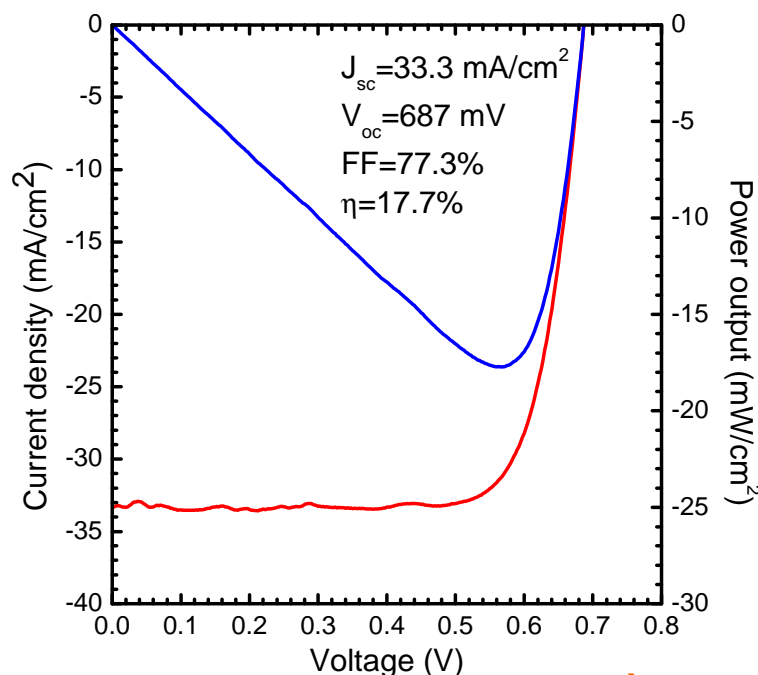
HIT solar cell concept

Heterojunction with Intrinsic Thin film (HIT) solar cell: the n+ region is not created by high temperature diffusion but by deposition of phosphorus-doped amorphous silicon (a-Si) film. A thin intrinsic a-Si film is deposited in between to improve surface passivation.



HIT solar cell results

| Affiliation | η (%) | V_{oc} (mV) | J_{sc} ($\text{mA} \cdot \text{cm}^{-2}$) | FF (%) | A (cm^2) | Status | Year |
|-----------------------------------|------------|---------------|--|--------|---------------------|--------|------|
| EPFL [123], Switzerland | 19.7 | 717 | 37.9 | 72.7 | 4, FZ | – | 2011 |
| NREL [71], USA | 19.3 | 678 | 36.2 | 78.6 | 0.9, FZ | IC | 2010 |
| Titech [148] [#] , Japan | 19.1 | 680 | 36.6 | 76.9 | 0.8, FZ | PR | 2011 |
| HZB [149], Germany | 18.5 | 633 | 36.8 | 79.1 | 1 | PR | 2009 |
| Univ. Stuttgart [150], Germany | 18.1 | 670 | 35.7 | 75.6 | 2 | – | 2010 |
| LPICM [151], France | 17 | 662 | 33.0 | 77.6 | 25, Cz | PR | 2009 |
| ENEA [152], Italy | 17 | 601 | 37.1 | 76.3 | 2.25 | PR | 2004 |



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Mille-Feuille concept

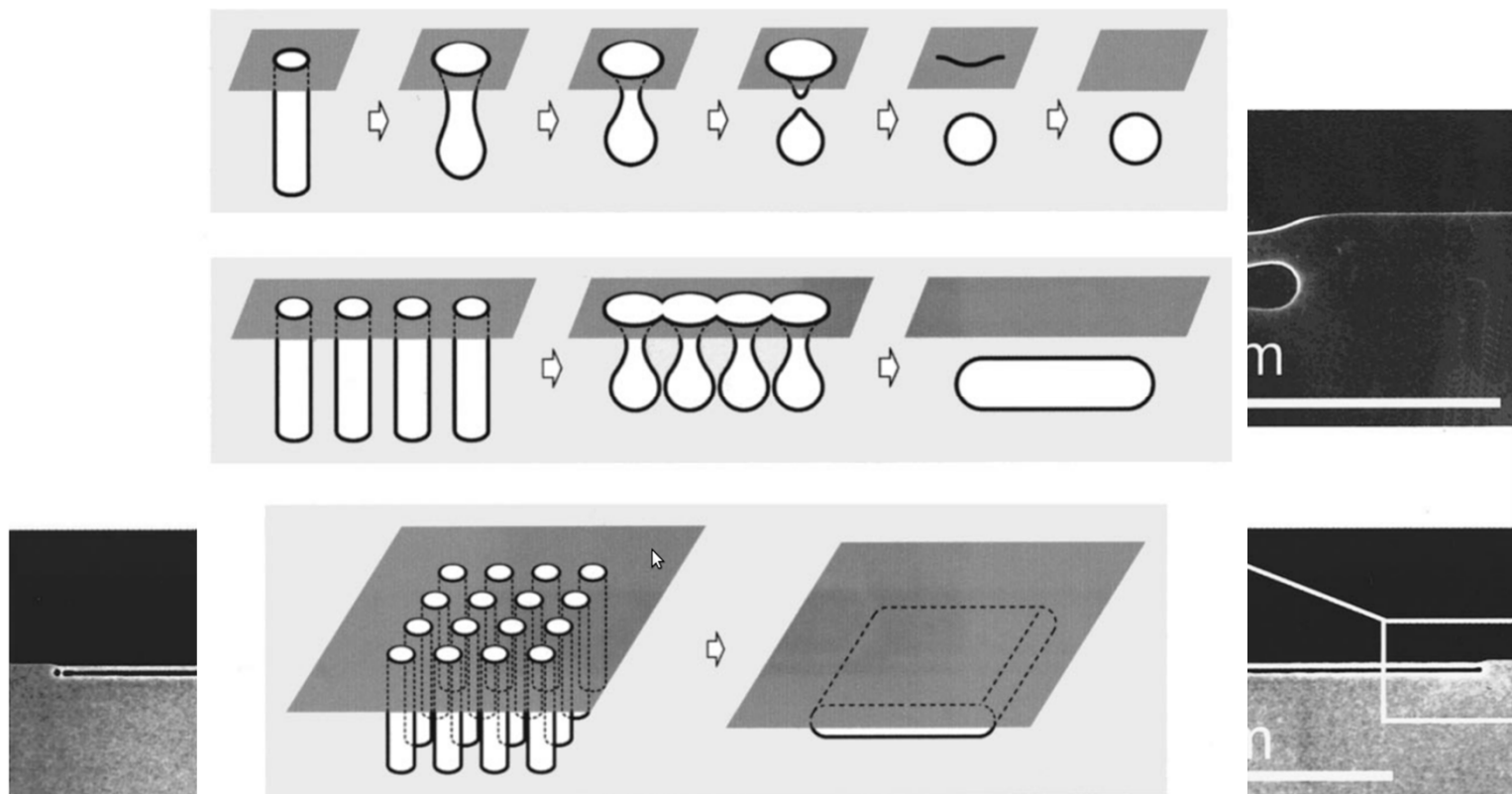
Objective: very thin ($<40\ \mu\text{m}$) high quality c-Si films from reusable c-Si substrates.



M. Garín *et al.*
presented at 28th
EUPVSEC,
Paris (2013)

State of the art.

Empty-space-in-silicon (ESS) technique

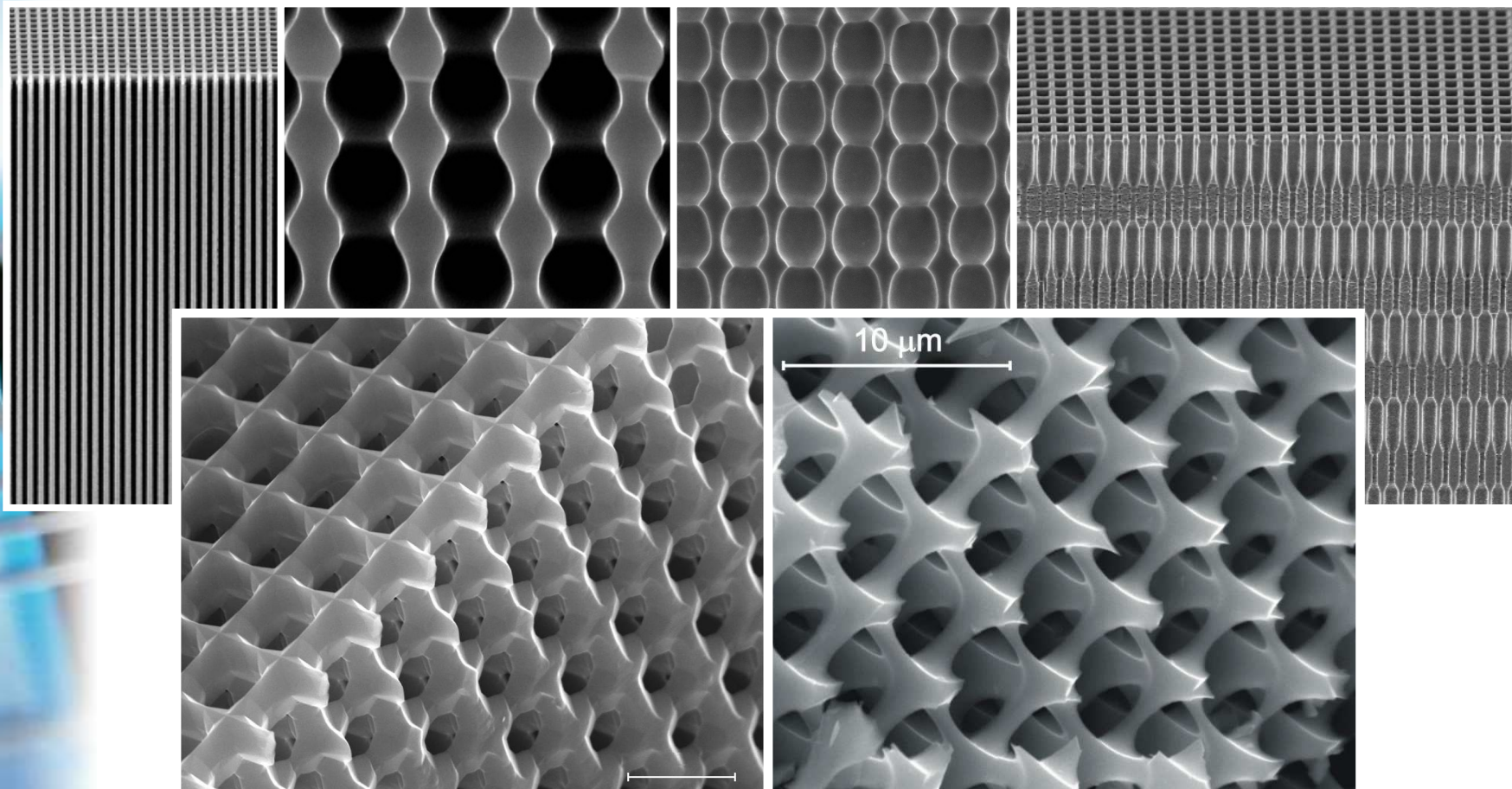


I. Mizushima, *et al.* Appl. Phys. Lett. **77**, 3290 (2000)

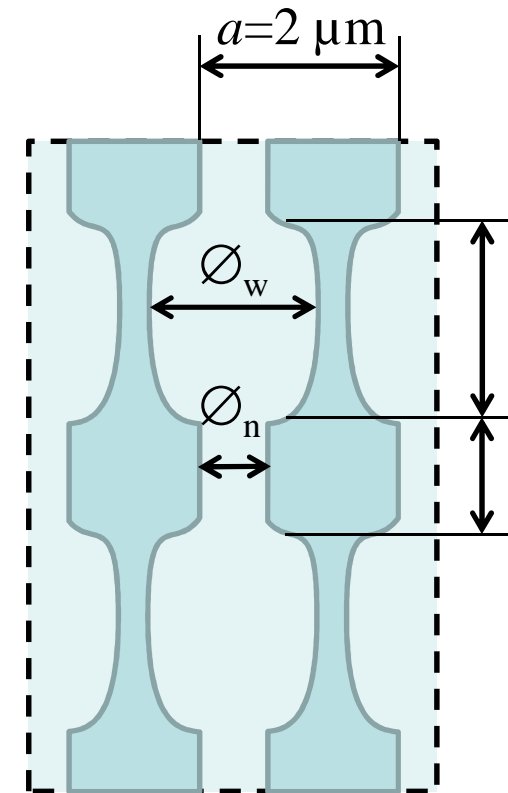
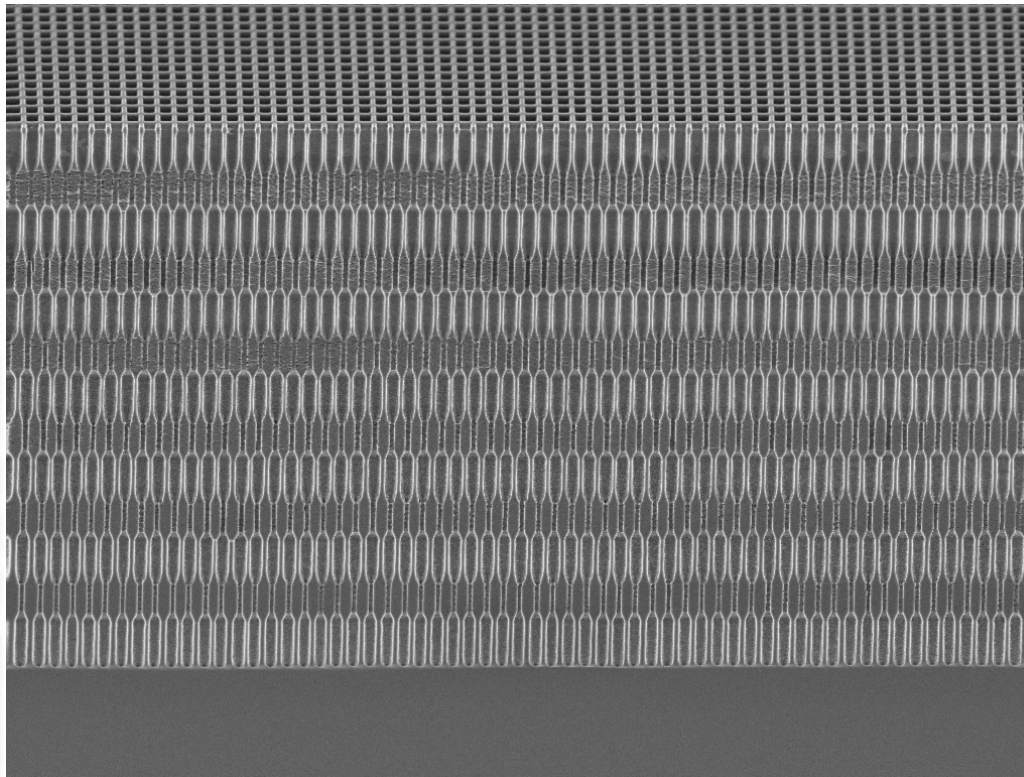
T. Sato, *et al.* Jpn. J. Appl. Phys. **43**, 12 (2004)

Process and Manufacturing Engineering Center, Toshiba Corp., Japan

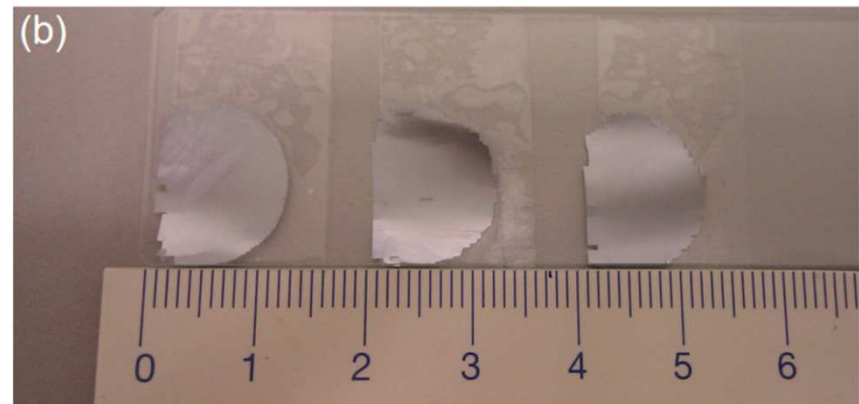
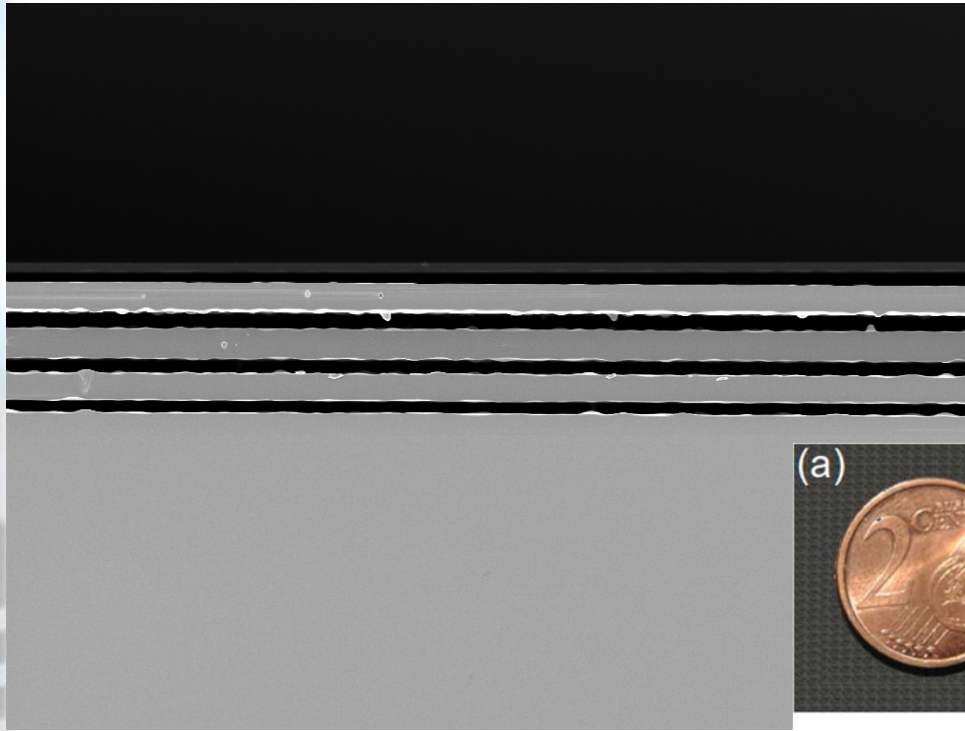
The fine art of etching pores in c-Si



Initial pore profile



Several free standing c-Si layers



Summary of mille-feuille characteristics

Monocrystalline

Roughness:

Ra: 0.11 μm

Rq: 0.14 μm

Rt: 1.05 μm

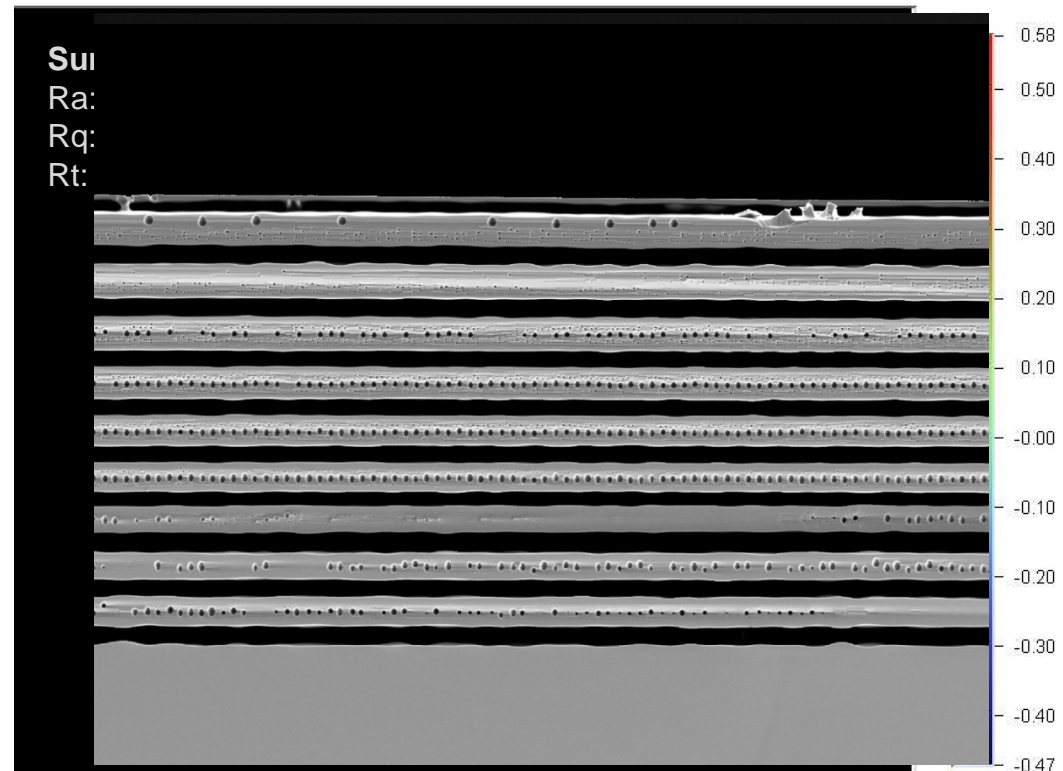
Thickness

$\leq 6.5 \mu\text{m}$

Up to 35 μm

with voids inside

Up to 10 layers

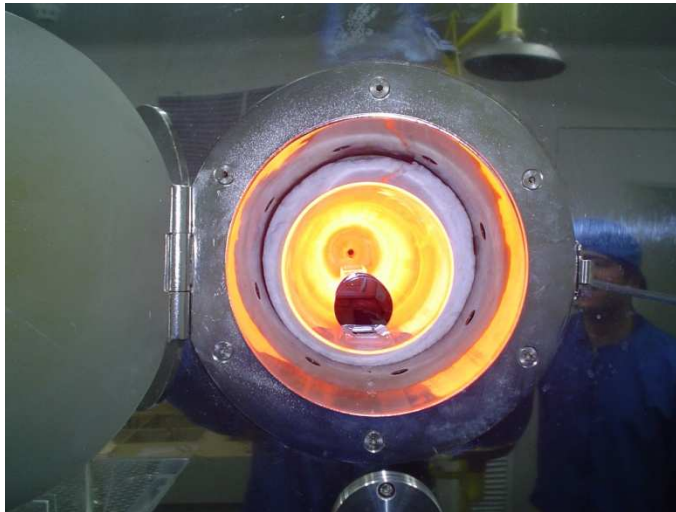


Outline

1. Introduction, description of the problem and objectives
2. Laser processing applied to rear contact schemes
 - Laser fired contacts with Al films
 - Laser doped regions from dielectric films: Al_2O_3 and $\text{SiC}_x(\text{n})$ films.
3. Fully low temperature structures
 - DopLa (Doped by Laser) cell.
 - IBC (Interdigitated Back Contacted) cell.
 - Silicon Heterojunction solar cells.
4. Very thin c-Si wafers: mille-feuille concept
5. Resources

Resources: clean room

- Diffusion and oxidation furnaces
- PECVD(a-Si, a-SiCx, a-SiN, SiO₂)
- Thermal evaporation + e-gun
- 2 RF Sputtering reactors
- Lithography 2 μm
- 1064 nm Nd-YAG laser



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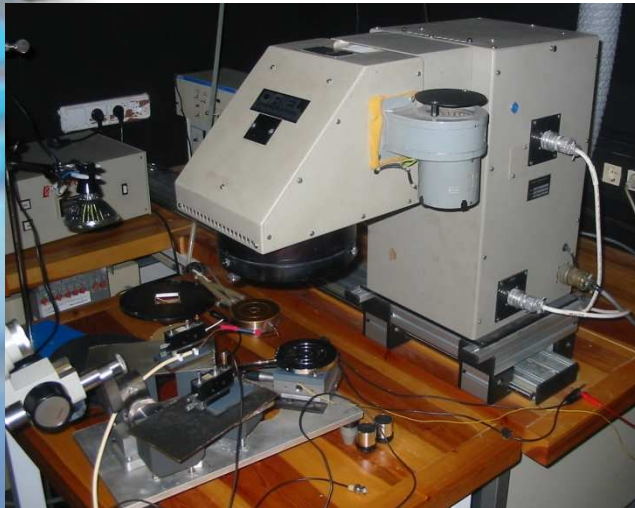


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Resources: device characterization lab

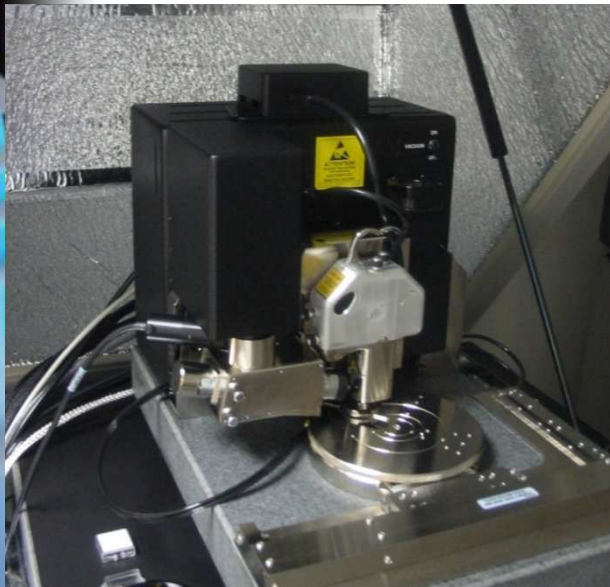
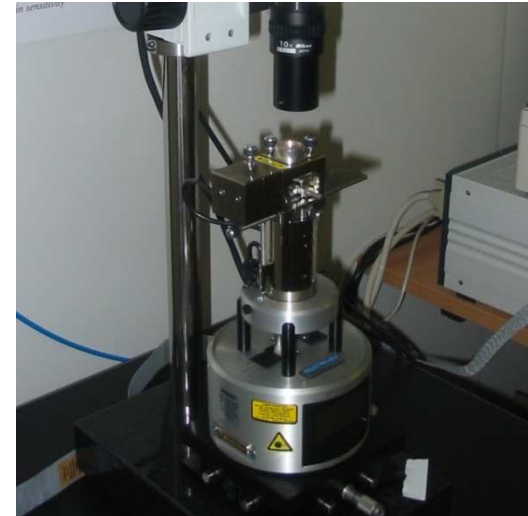
- Electrical characterization (I-V-T, C-V, solar simulator, $\tau_{\text{eff}}(\Delta n)$, etc.)
- Optical characterization (spectrophotometer, EQE, etc.)
- Solar simulator.
- Cryostat.



Resources: nano-scale characterization

Centre recerca en nano-enginyeria (CrNE).

- Atomic Force Microscopes
- Mechanical Profiler
- Optical Surface Profiler
- SEM/FIB
- XPS



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DOCTORATE PROGRAM IN **ELECTRONIC ENGINEERING**

DOCTORAL TRAINING SEMINARS: RESEARCH PROJECTS IN
THE DEPARTMENT OF ELECTRONIC ENGINEERING

**“Cost-effective technologies for crystalline
silicon (c-Si) solar cells”**

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(isidro.martin@upc.edu)

11th February 2014

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